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**Particle size analysis — Laser
diffraction methods**

Analyse granulométrique — Méthodes par diffraction laser





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CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
Website: www.iso.org

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Foreword

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This document was prepared by Technical Committee ISO/TC 24, *Particle characterization including sieving*, Subcommittee SC 4, *Particle characterization*.

This second edition cancels and replaces the first edition (ISO 13320:2009), which has been technically revised. The main changes compared to the previous edition are as follows:

- a) protocols for evaluation of accuracy and qualification of instrument were newly developed;
- b) new [Annex H](#) (normative) for usage of reference material has been added;
- c) new descriptions for wider applications, such as off-line, online, in-line and at-line have been added;
- d) some informative parts have been moved to new annexes;
- e) minor revisions and updates have been made throughout the document.

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